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L3	0	THOMAS-BRANDY-M.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 19:43
L4	1	YOUNG-CHRISTOPHER-D.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 19:43
L5	13	MOORE-RICHARD-P.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 19:44
L6	0	BIRO-ROSS-A.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 19:44
L7	0	PEMBERTON-ALISSA-S.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 19:45
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L1	81092	((("709"/(203,223-224,217-219).ccls.) or ("707"/("1,3,5,10").ccls.))) and @ad<"20000523"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 14:18
L2	331	(benchmark\$1! with (entity or entities or company or companies or organization\$1! or corporation\$1! or buniness\$2! or entrepreneur\$1!))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 14:32
L3	31	1 and 2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 15:30
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L9	0	8 and @ad<"2000523"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/20 15:42
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